## **DESIGN AUTOMATION & EMBEDDED SYSTEMS**



SECURITY/FPGA - EMBEDDED - INTERNET OF THINGS - ELECTRONIC DESIGN/PRODUCTION - TESTING

## Testen van Embedded Systemen

Gerard Fianen



## INDES-IDS BV - Embedded Software Development















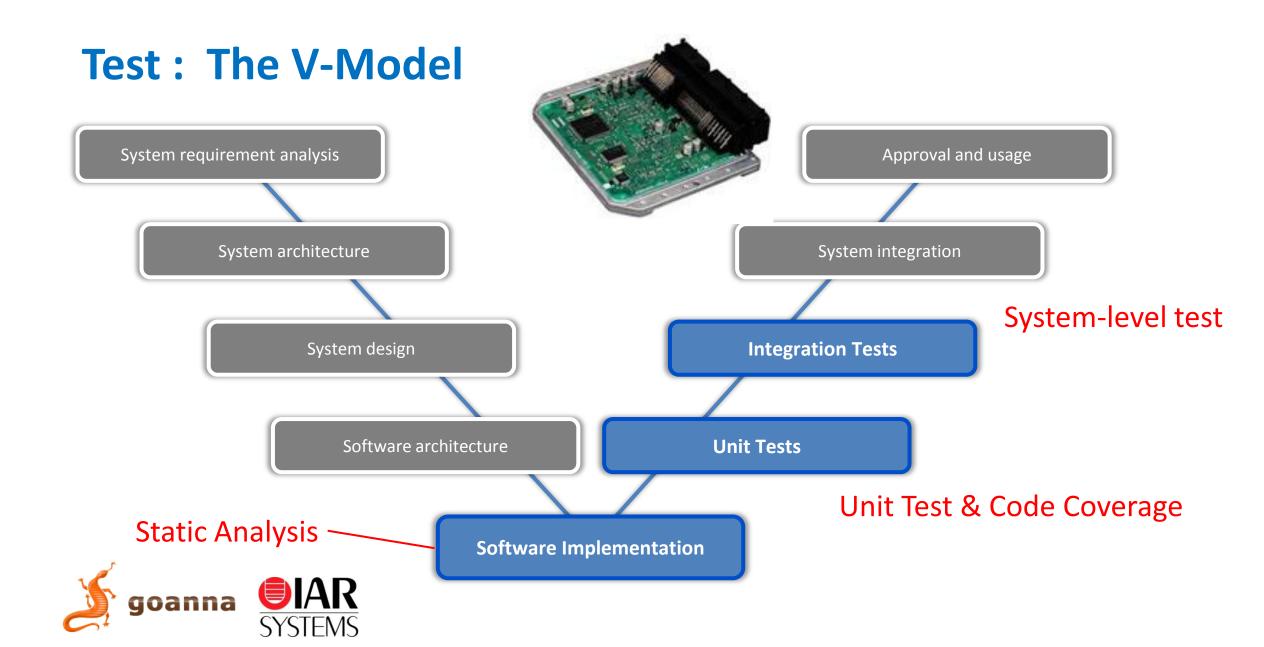






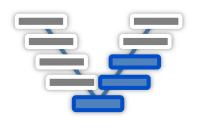


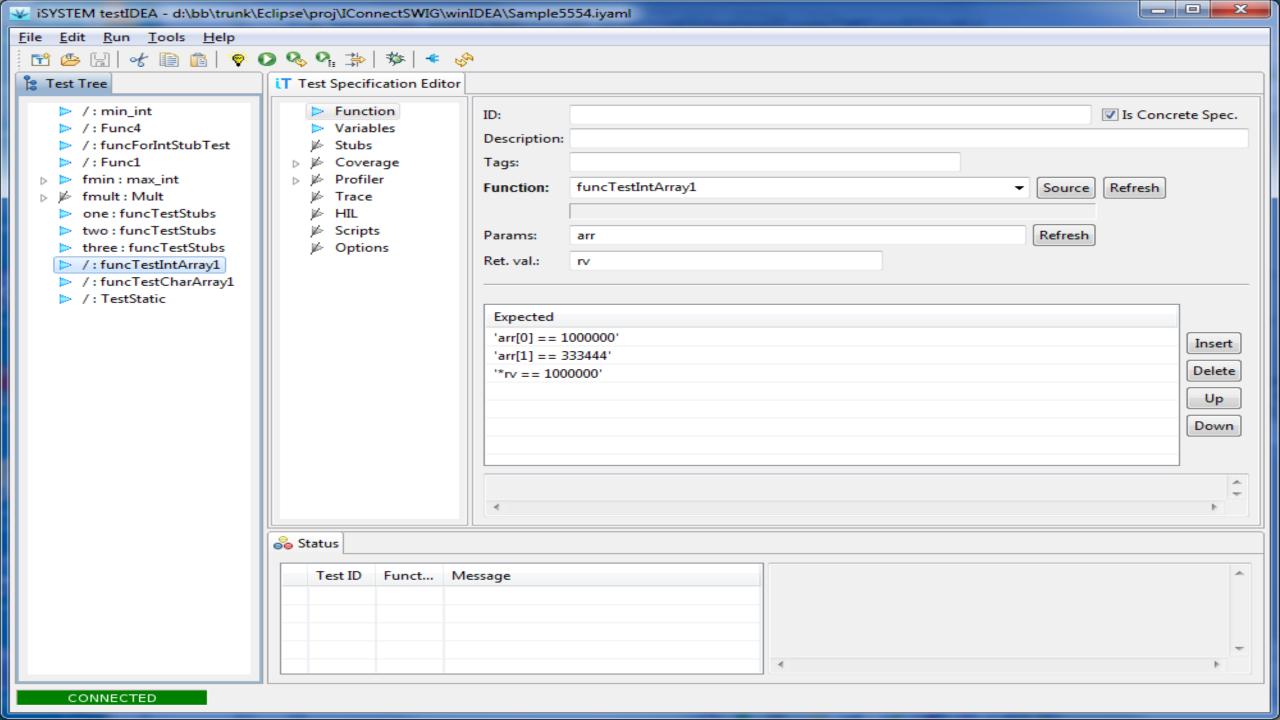
Tel: 0345 - 545.535





• What is Unit Test?







- What is Code Coverage ?
  - SC (Statement Coverage)
  - BC / DC (Branch / Decision Coverage)
  - CC (Condition Coverage)
  - MCDC (Modified Control Decision Coverage)

Build an automatic regression Testsuite



Coverage Criteria	Statement Coverage	Decision Coverage	Condition Coverage	Condition/ Decision Coverage	MC/DC	Multiple Condition Coverage
Every point of entry and exit in the program has been invoked at least once		•	•	•	•	•
Every statement in the program has been invoked at least once	•					
Every decision in the program has taken all possible outcomes at least once		•		•	•	•
Every condition in a decision in the program has taken all possible outcomes at least once			•	•	•	•
Every condition in a decision has been shown to independently affect that decision's outcome					•	• <sup>8</sup>
Every combination of condition outcomes within a decision has been invoked at least once						•

## for embedded systems

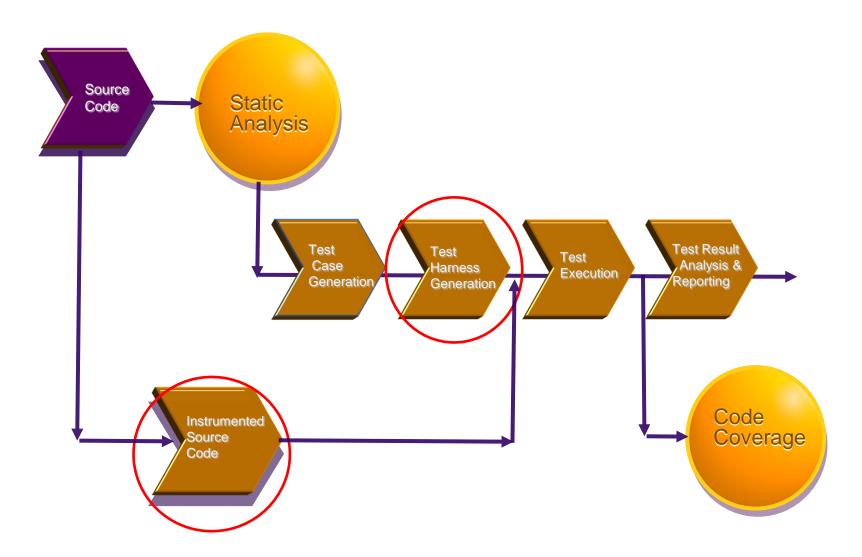


On-Host testing versus On-Target Testing

Real-Time versus non\_Real-Time

## **Traditional workflow**





```
static void countProducts(void)
 struct CountedProduct * currentCountedProduct;
 uint32 t iProduct = 0U;
 const struct Product * currentProduct;
 ProductDatabase resetCountedProducts();
 /* iterate over each product that has been scanned */
 while (iProduct < scannedProducts) {</pre>
  currentProduct = ShoppingBasket[iProduct];
  if ( currentProduct != NULL_POINTER )
   currentCountedProduct = ProductDatabase getCountedProduct(currentProduct);
   if (currentCountedProduct != NULL POINTER)
     (currentCountedProduct->count)++;
  iProduct++;
```



```
met instrumentatie:
static void countProducts ( void)
   int iCashregister 7zzggzz = Cashregister 7zzggzz ( 6 ) ; /
* 37 */
    struct CountedProduct * currentCountedProduct;
    uint32 t iProduct = 0U;
    const struct Product * currentProduct ;
    ProductDatabase resetCountedProducts () ;
    /* iterate over each product that has been scanned */
    while ( iProduct < scannedProducts )
 { /* 32 */
        currentProduct = ShoppingBasket [ iProduct ] ;
        if ( currentProduct != ( ( void * ) 0 ) )
            currentCountedProduct =
ProductDatabase getCountedProduct ( currentProduct ) ;
            if ( currentCountedProduct != ( ( void * ) 0 ) )
                ( currentCountedProduct -> count ) ++ ;
else
 Cashregister 7zzqqzz ( 7 ); /* 4 */
else
  Cashregister 7zzggzz ( 8 ); /* 4 */
        iProduct ++ ;
    Cashregister 7zzggzz ( 9 );} /* 6 */
    Cashregister 7zzggzz ( 10 ) ; /* 5 */
    Cashregister 7zzggzz ( 11 ) ; /* 30 */
```



## **Problems with instrumentation**

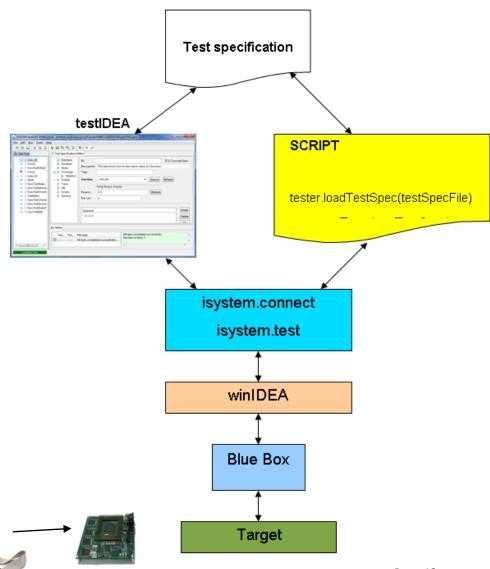


- Often tricky to integrate into the build process
- Code size increases
- Execution times are different
- Not all functions can be tested (drivers)
- Certification of the instrumenter (more complex TQP)

## **Alternative approach**

- Integrate with the debugger
  - Full open API to all debugger functions
  - Fully integrated Unit Test creation
- Automate the process
- For coverage : Use Real-Time Trace
  - ETM, Nexus, Aurora, Full ICE



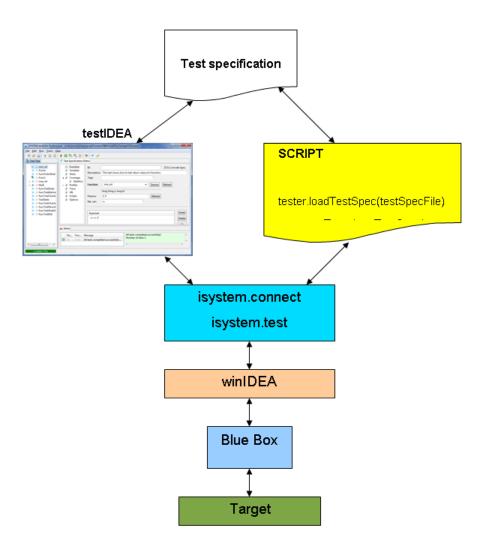






## **Benefits**

- No instrumenter in the build process
- Test execution on the target system
- Test execution on the production code
  - on Machine code level
  - Cross compiler v.s. host-compiler
- No test driver / test harness needed
- Continuous code coverage Code coverage
- Fully integrated with Development process
  - Development engineer can develop the tests





## **Examples of advanced features**

- Compare 'golden' with current Real-Time Execution trace
- Combine trace, performance analysis, code coverage and I/O stimuli with test runs
- Technology may be used for unit, integration and system test



## System test

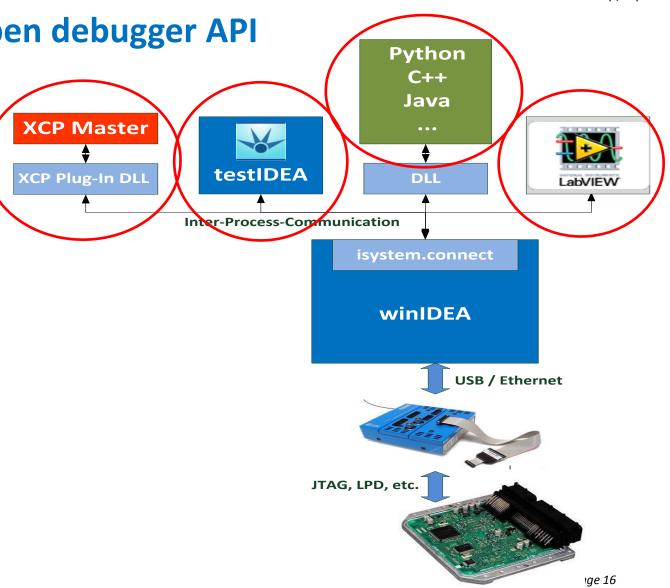


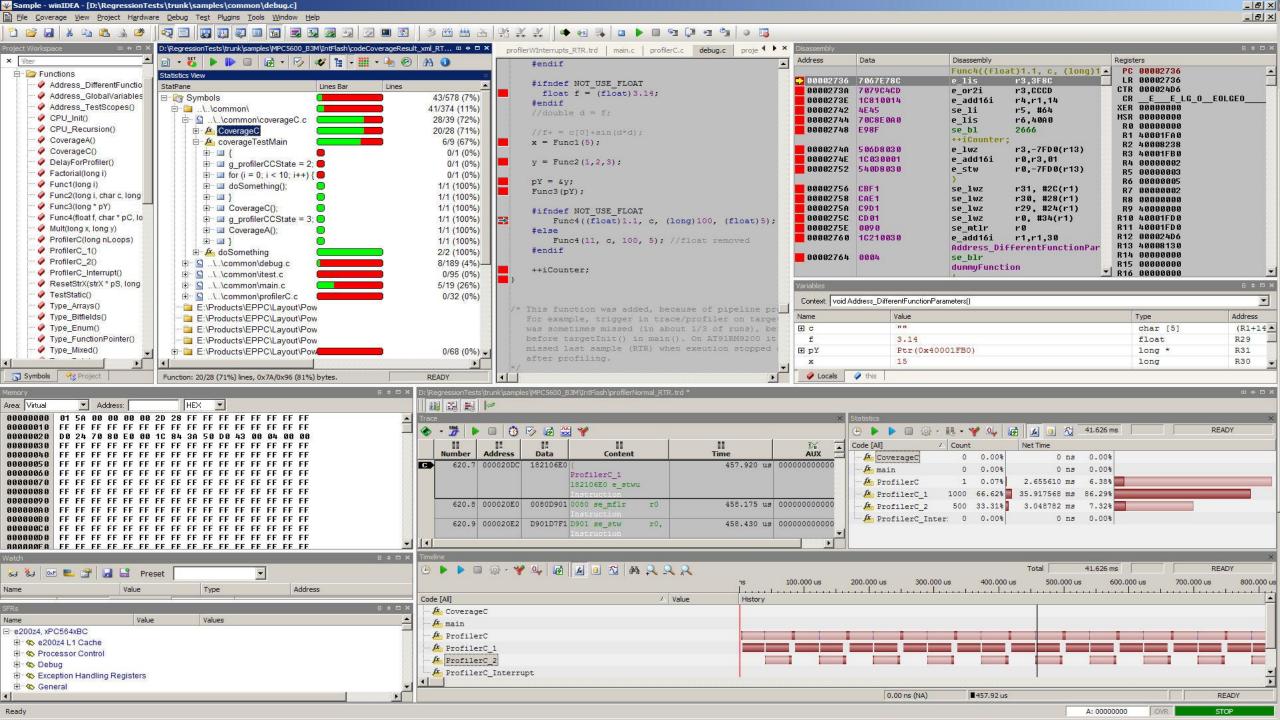
take advantage of the open debugger API

### **Available Features:**

- Debugging:

   Download, Run/Stop, Break
   Symbol Information
   Read/Write Data Access
- Analysis: Trace Coverage Profiling
- IDE and Build System
- All testcases are parametric



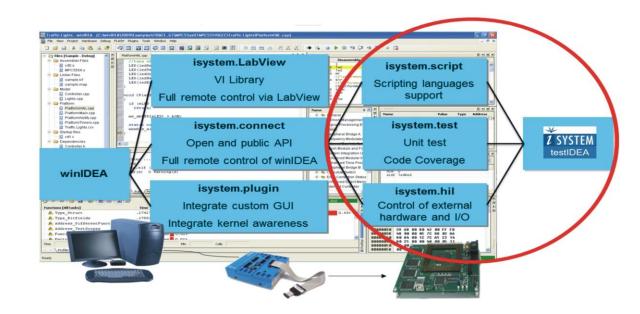


## **System test**

## Benefit of using debugger API

- Very easy to do complex tests
  - Debugger knows 'everything'
  - Real-time access to memory, registers, variables, peripherals
  - All during Real-Time execution
- Simplifies System test fixtures
- All test cases are parametric
- Easy reuse of test cases

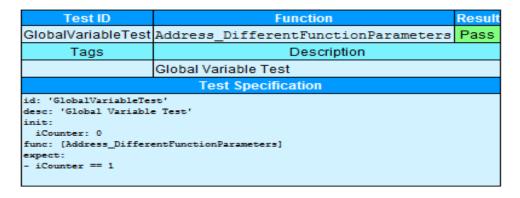


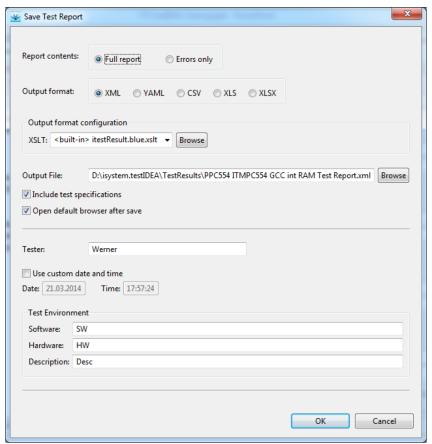


### iSystem Test Results

Test Configuration					
Attribute	Value				
report file	D:\winIDEA\2011\Examples\OnChip\PowerPC\MPC55xx\ITMPC5554\GCC\IntRAM\EroIsersterReport.xmI				
tester	Erol				
date	20.06.2011				
time	16:58:15				
software	SW				
hardware	HW				
description	Desc				
testSpecificationFile	D:\winIDEA\2011\Examples\OnChip\PowerPC\MPC55xx\ITMPC5554\GCC\IntRAM\PPC5554 ITMPC5554 GCC Int RAM.iyaml				
wiWorkspacePath	D:\winIDEA\2011\Examples\OnChip\PowerPC\MPC55xx\ITMPC5554\GCC\IntRAM				

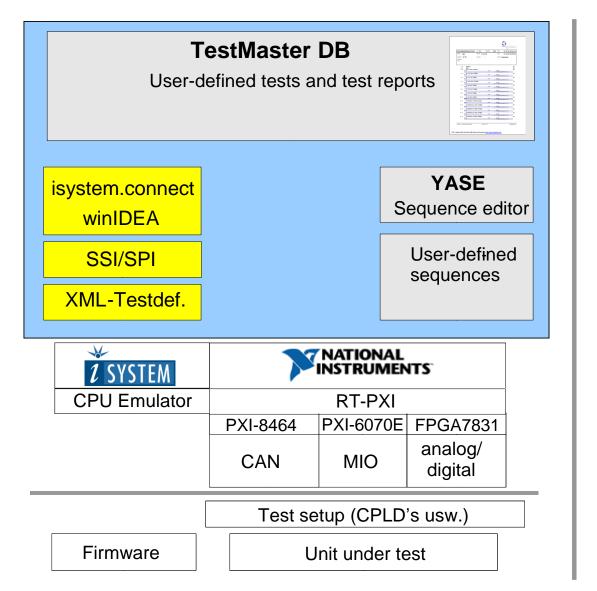
Test ID	Function	Result			
	Address DifferentFunctionParameters				
Stubiest	Address_DifferentrunctionFarameters	Газэ			
Tags	Description				
	Stub Test				
	Test Specification				
desc: 'Stuinit:     iCounter func: [Add stubs:     - Func:     - Func2     - retV     assign:     retV: expect:     iCounter	: 0 ress_DifferentFunctionParameters] 2				





## **Example:** Hella (part of CASA@HELLA)





Configuration
Test definition

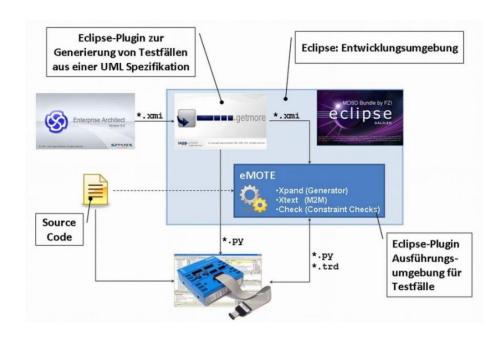
Measurement system

FIT Hardware

## **Advanced example:**



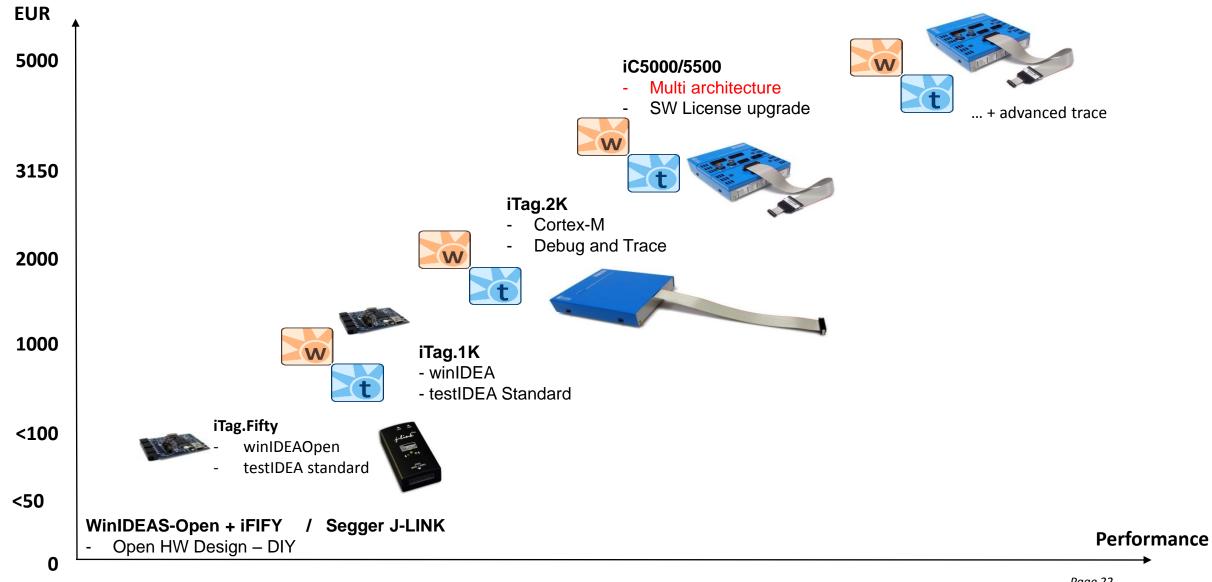
## eMOTE:\*E\*mbedded \*Mo\*del-based \*Te\*sting



- Funded by BMWi Germany
- Project partners: FZI Karlsruhe, sepp.med GmbH
- Project Number: KF2076903SS9



## Wat kost dat?



## WinIDEA Open

## experience the environment yourself

Free Cortex-M software development and test platform supporting iSYSTEM's Cortex Tool <u>iTAG</u>, different 3rd party debug hardware (e.g., <u>SEGGER J-Link</u>, <u>ST-LINK</u>, CMSIS-DAP) and a large number of evaluation boards. winIDEA Open supports all major compilers and imposes no code size restrictions when used with the GNU toolchain (32K others) and is provided with no support. Therefore it is recommended to use winIDEA Open for evaluation and non-critical projects only.

#### Overall software features (no time or code size limitations):

Full GNU GCC toolchain 4.7 included Unlimited code size with GCC compiler Full featured winIDEA platform:

- Editor & build manager
- Flash programming
- HW and SW breakpoints
- Low and high-level debugging
- Device register view (SFRs)
- Python scripting
- Test tool testIDEA standard included (Unit Test / Code Coverage)
- RTOS aware debugging
- Interoperable with a wide range of tools through isystem.connect API

Optional upgrade to commercial winIDEA build (all compilers supported, full technical support, regular winIDEA updates, support for new microcontrollers, new winIDEA functionalities, ...). To upgrade, please INDES-IDS BV.

## WinIDEA Open

Download WinIDEA-OPEN at: <a href="http://isystem.com/index.php/download/winideaopen">http://isystem.com/index.php/download/winideaopen</a>

winIDEA Open currently supports the <u>iSYSTEM iTAG.ZERO and iTAG.FIFTY</u> as well as various third party debug hardware such as the <u>SEGGER J-Link</u>, <u>ST-LINK</u> and CMSIS-DAP in conjunction with many evaluation boards, see <a href="http://isystem.com/index.php/products/software/winidea-open">http://isystem.com/index.php/products/software/winidea-open</a>



## **Voor meer informatie:**

**Gerard Fianen** 

gerard@indes.com

Tel: 0345 - 545.535

www.indes.com/embedded



# **Supporting slides**



### More detailed information on Unit Test

Debugger knows 'everything'

Real-time access to memory, registers, variables, peripherals

All during Real-Time execution

More detailed information on Code Coverage using trace

More on Certification

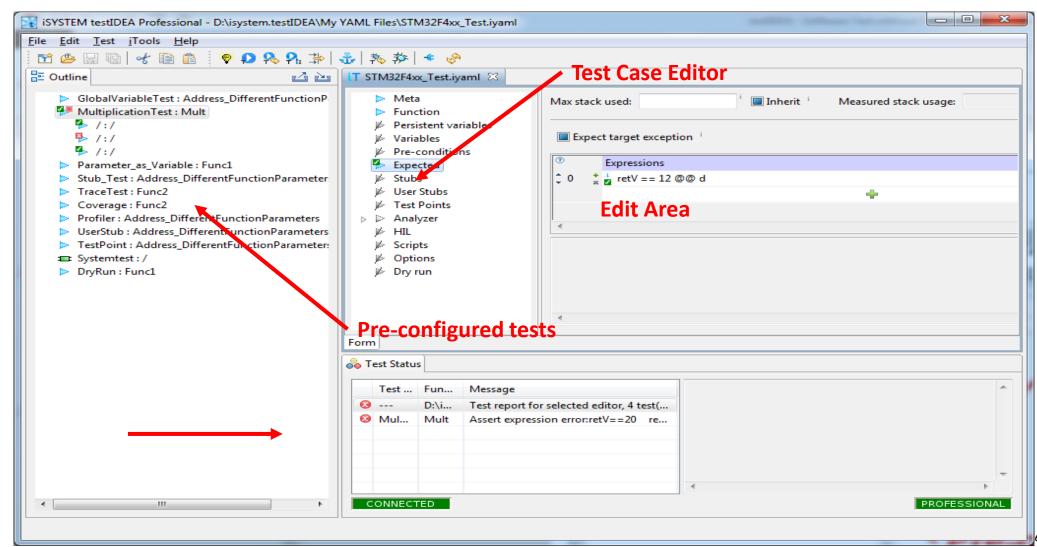


## iSYSTEM Test Possibilities





# testIDEA in conjunction with winIDEA



Results

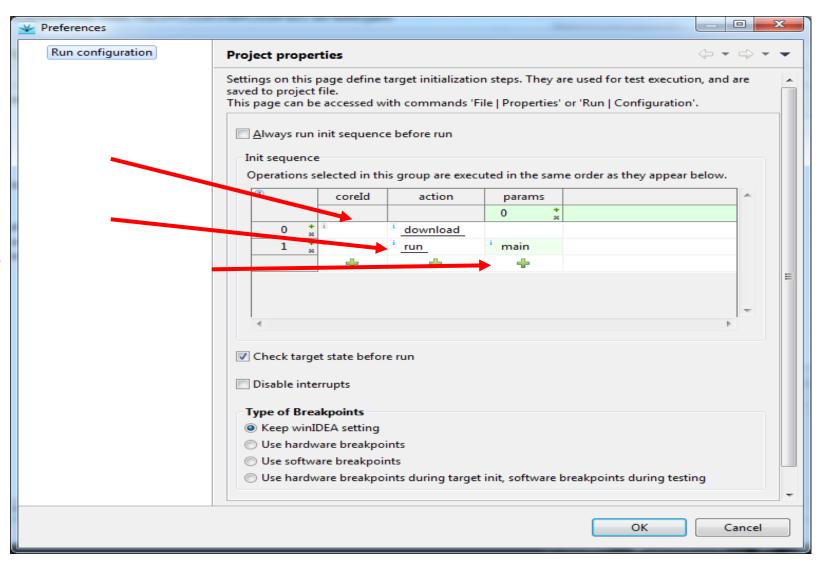


# testIDEA Basic Configuration

Which core?

What to do?

Which parameter?



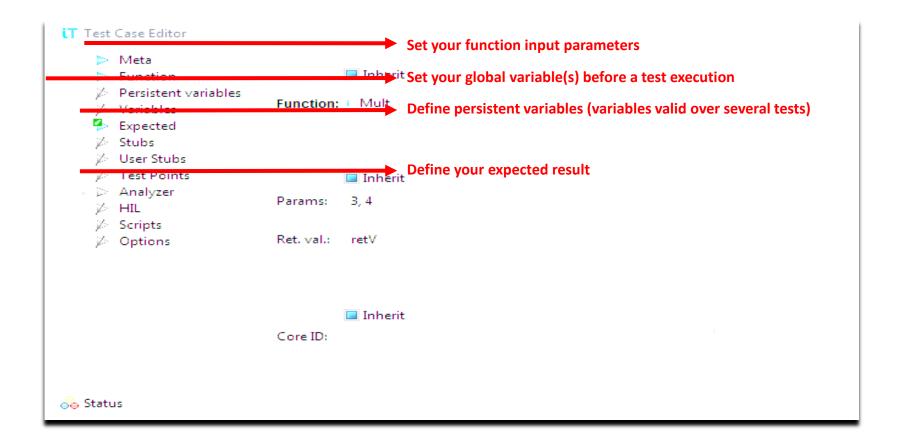
# Input Parameters / Expected Return Values



#### Input Parameters can be

- Function Parameters
- Global Variables
- Persistent Variables

**Expected Return Value** 



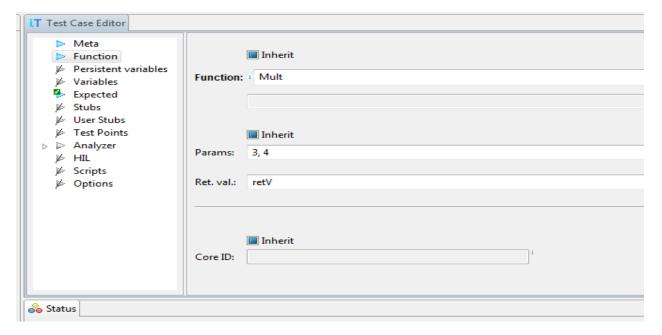
# Input Parameters / Expected Return Values



#### Input Parameters can be

- Function Parameters
- Global Variables
- Persistent Variables

#### **Expected Return Value**



#### **Test Specification as text:**

- id: FunctionTest
 desc: | My Function Test
 init:
 iCounter: 0
 func: [Mult, [3, 4], retV]
 expect:
 - 'retV == 12'

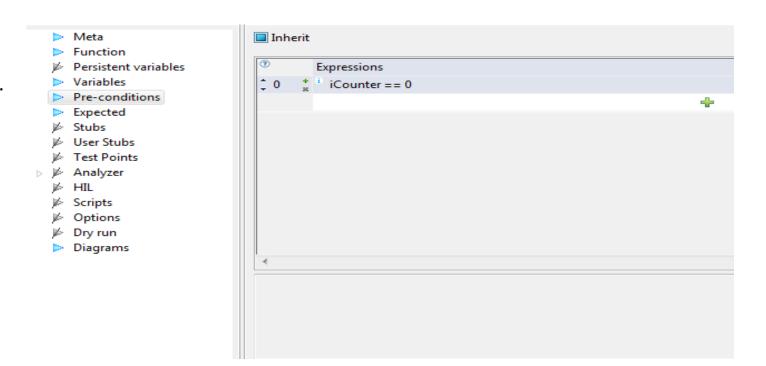


## **Pre-Conditions**

This section contains expressions, which are evaluated before test case execution is started.

This functionality can be used, when certain global variables or hardware input values must match some criteria for test to succeed.

If we detect error early, it is easier to find the reason for test failure.





## Stubs

#### Method stub (From Wikipedia)

A method stub or simply stub in software development is a piece of code used to stand in for some other programming functionality. A stub may simulate the behavior of existing code (such as a procedure on a remote machine) or be a temporary substitute for yet-to-be-developed code. Stubs are therefore most useful in porting, distributed computing as well as general software development and testing.

#### Typical Use Cases in testIDEA:

- 1. Replace a function call with a return value -> the function is not called, the return value is set (not real time)
- 2. Do nothing a function call is simply ignored (real time)
- 3. A function call is replaced with another function call (real time). The replaced function is already a part of the downloaded code.



# Stubs

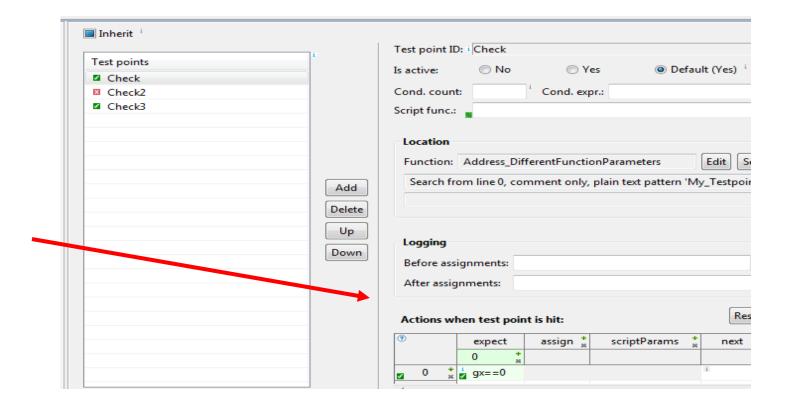
iT Test Case Editor				
▶ Meta	■ Inherit i			
Function			Stubbed func.:	Func1 Source
Persistent variables	User Stubs	1	Stubbeu fulle	June 30dice
	Func1			
Expected			In matinus	○ No  ○ Yes  ○ Default (Yes) i
⊯ Stubs			Is active:	O NO O YES O DETAUL! (YES)
User Stubs			Stub type:	Call target function
			Stub type.	© can target runetion
			D1	i Detail Comm
⊯ HIL			Replacement f.:	Func2 • Refresh Source
		Add		
		700		
		Doloto		



# Test points

Test points pause test execution at any location in the tested code and perform a certain action. This could be

- Anything you can do with a debugger like read/write Memory, etc.
- Modify Variables, Function
   Calls (-> Fault Injection)
- Logging
- Use a script for modification





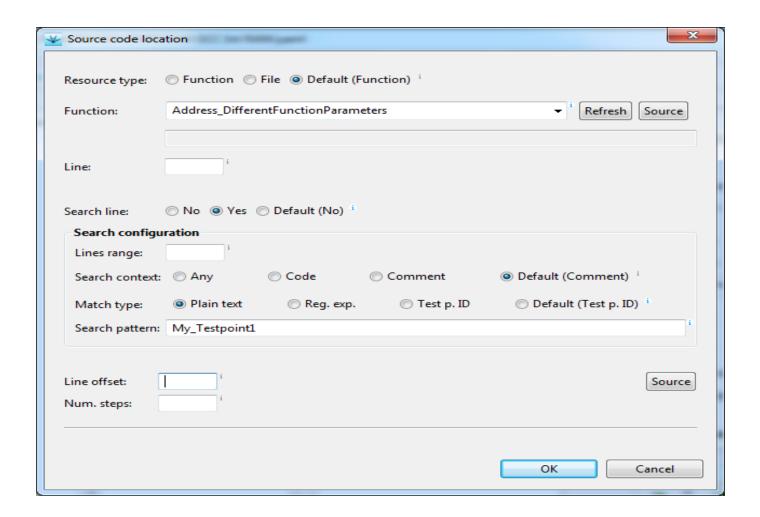
# Test points

#### Where to stop?

Base could be a file name (module.c) or a function name.

- Line Number (not recommended because they could change after a rebuild)
- Search Pattern
- Test ID

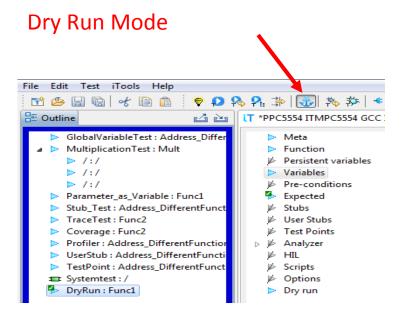
```
337 x=Func1(5); //+c[1];
338 gx=x; //My_Testpoint1
339
340 v=Func2(1 2 3): //My_Testr
```

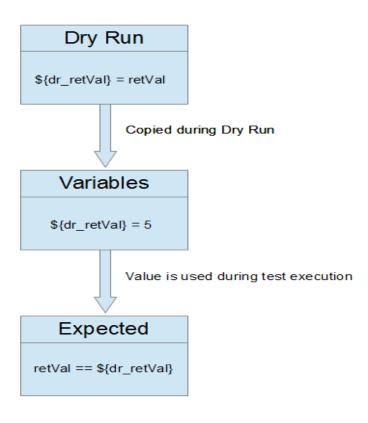




#### Dry Run

This functionality can be used to record behavior of existing and tested target code and use the result for the next test run.





#### Charts

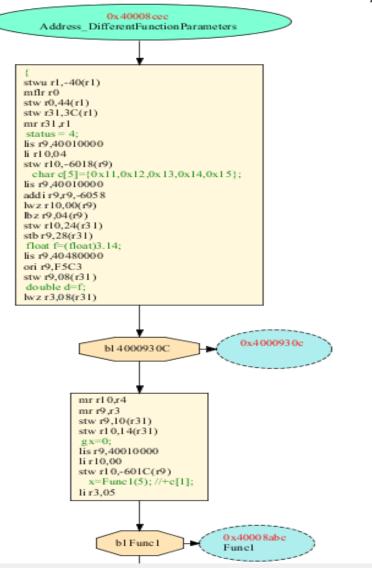
#### **Flow Chart**

A flowchart is a type of diagram that represents the program flow of the function under test.

The information is based on the downloaded code, not on the executed code.

In general flowcharts are used in analyzing, designing, documenting or managing a process or program in various fields.





Page 38

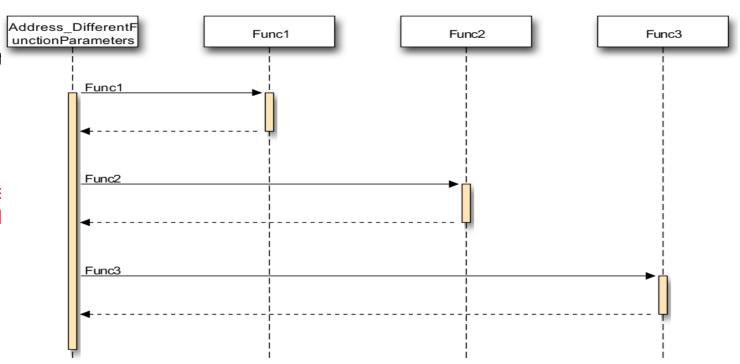


#### Charts

#### **Sequence Diagram**

A Sequence diagram is an interaction diagram that shows how processes operate with one another and what is their order. A sequence diagram shows object interactions arranged in time sequence.

The information is based on the profiled data(time measurement) and shows what was executed and when during the test execution.



Sequence diagrams are typically associated with use case realizations in the Logical View of the system under development. Sequence diagrams are sometimes called event diagrams or event scenarios.



#### Charts

#### **Call Graph**

A call graph is a directed graph that represents calling relationships between subroutines in a computer program.

Call graphs are a basic program analysis result that can be used for human understanding of programs, or as a basis for further analyses, such as an analysis that tracks the flow of values between procedures.

One simple application of call graphs is finding procedures that are never called.

# Address\_DifferentFunctionParameters Func3 Func1 Func2

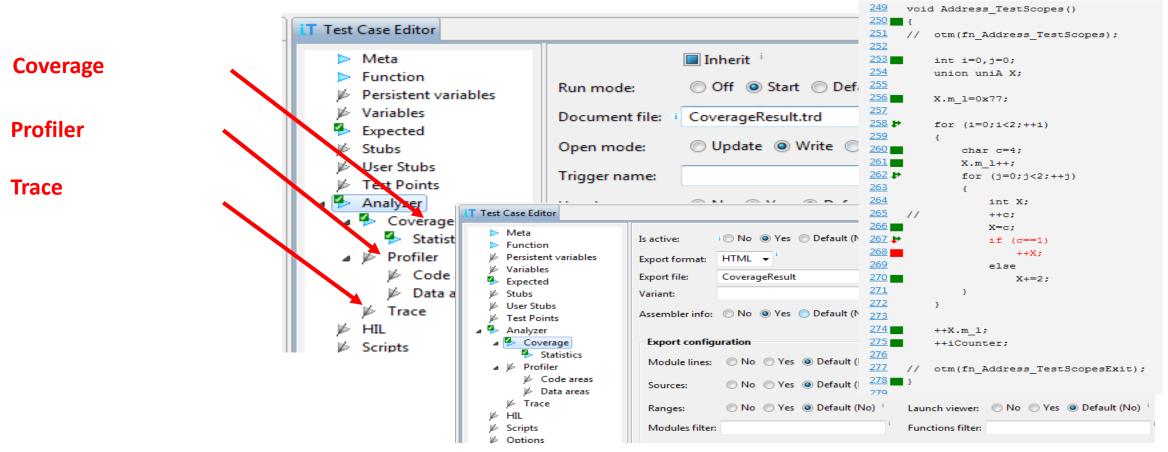
Call graphs can be dynamic or static. A dynamic call graph is a record of an execution of the program, e.g., as output by a profiler. Thus, a dynamic call graph can be exact, but only describes one run of the program.

In our case the information is based on the profiled data / executed code.



## Analyzer

Any test action in testIDEA can be combined with analyzer functionality:





## Analyzer

Even without trace possibility on the microcontroller, you still have analyzer possibilities:

	iT Test Case Editor			
l	▶ Meta	■ Inherit <sup>i</sup>		
	▶ Function ▶ Persistent variables	Run mode:	Off ⊚ Start ⊘ Default (Off) i	
		Document file: i	CoverageResult.trd	
	⊯ Stubs	Open mode:	○ Update ● Write ○ Append ○ Default (Write) i	
ı		Trigger name:	i	
		Use slow run:	○ No ○ Yes ○ Default (No) i	
	Statistics	Save after test:	No        Yes        Default (No) <sup>i</sup>	
		Close after test:	No Yes Default (No)   Default (No)	
	⊯ Trace			
	⊯ HIL			



## Code Coverage Functionality





#### **On-Chip Trace**

- ETB / OTB = Embedded / Onchip Trace Buffer
  - Limited buffer size (4KB to 1 MB)
  - Limited length of recording
- Trace Port (ETM, Nexus, Aurora)
  - Limitation depends on external hardware
  - Long term recording
  - Bandwidth (4-32Bit, LVDS signaling)



# Sampling Information in the Trace Buffer I



- A good trace system requires
  - An (emulation/umbrella) controller that provides visibility of the internal memory bus to the outside world (via dedicated trace bus or message port)
  - A trace buffer onchip or inside the debug system that stores the information from the controller and other sources in real-time and for a long time
  - A trigger that starts recording at dedicated conditions
  - A qualifier / filter that starts / stops recording in certain memory areas
  - Store the information in a file for documentation capabilities

## Sampling Information in the Trace Buffer II



Same technique and buffer is used for different purposes

• Trace: Record complete instruction flow

Profiling: timing Record complete instruction flow and show function

mixed with data

• Coverage: Record complete instruction flow and check against source code and determine for every instruction if executed or not





Code Coverage is a measure used in software testing.

#### You measure

- The quality of your code
- The size of executed code by a set of test cases
- The quality of your test cases

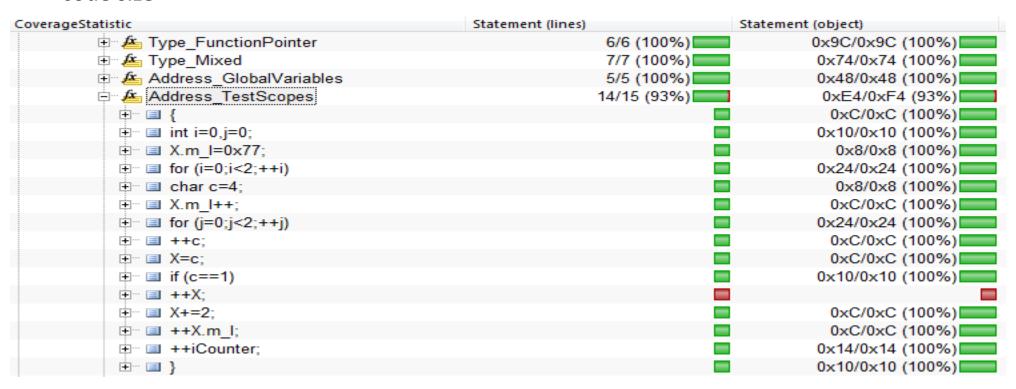
All Coverage Results at iSYSTEM are based on executed object code!





## Types of Coverage

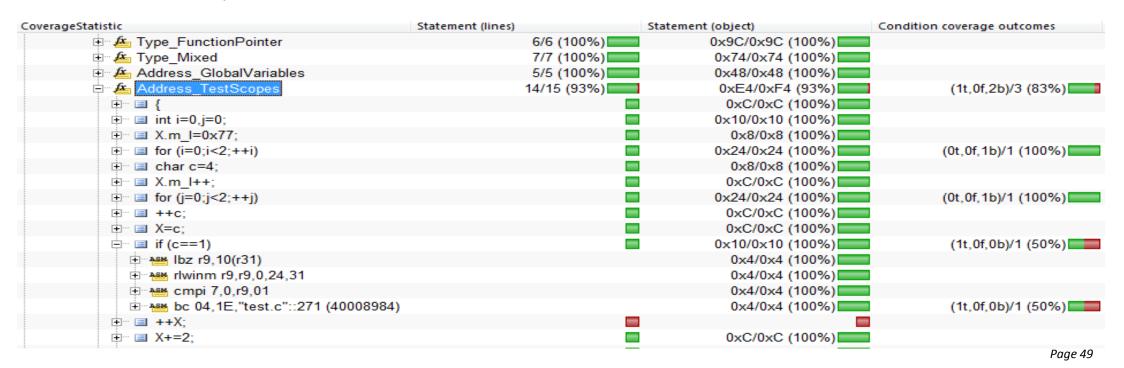
- Statement Coverage
  - marks statements or instructions as executed or not executed based on lines and based on object code size





## Types of Coverage

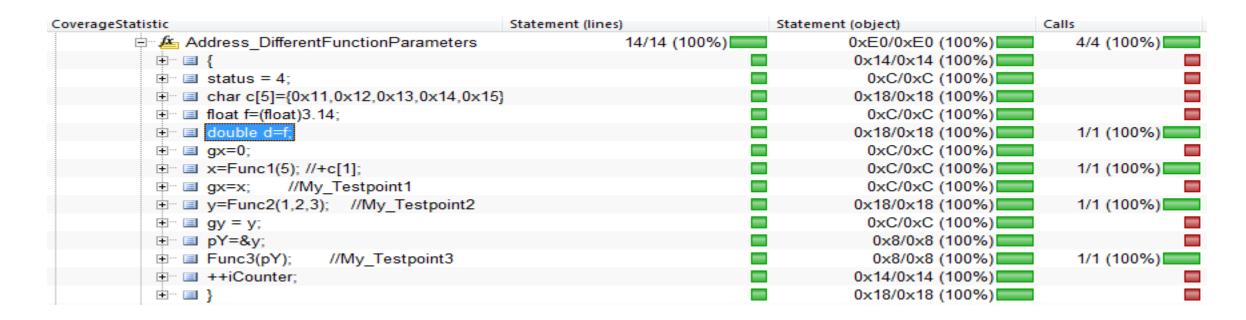
- Condition Coverage
  - Marks conditional branch instructions or conditional statements as
    - Executed
    - branch taken
    - branch not taken
    - both paths covered





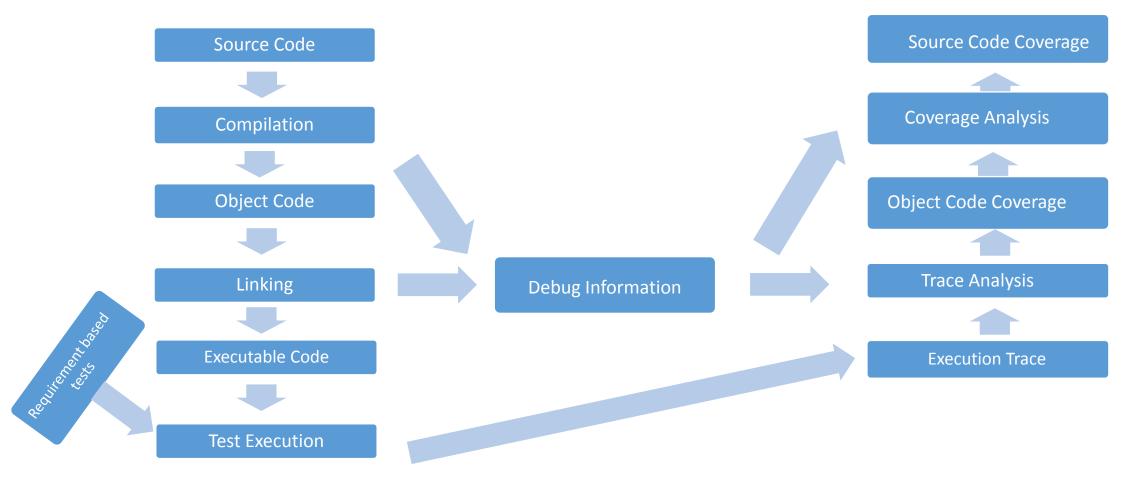
## Types of Coverage

- Call Coverage
  - Each (function) call is reported





## How is Code Coverage executed?





## How is Code Coverage executed?

#### In Words:

```
program execution + iSYSTEM tools
= program trace
```

program trace + disassembler information = object code coverage

			THEFT	.011			
5.0	40008B3C	D0FF2194	{			45.699 u	s
			Func2				
			9421FFD0	stwu	r1,-30		
5.1	40008B40	2C00E193	93E1002C	stw	r31,2C	45.705 u	3
5.2	40008B44	780B3F7C	7C3F0B78	mr	r31,r1	45.710 u	3
5.3	40008B48	18007F90	907F0018	stw	r3,18(1	45.715 u	3

```
297 long Func2(int i,char c, long 1)
298 {
299    int x=0;
300    long y=0;
301
302    for (;x<10;++x)
```





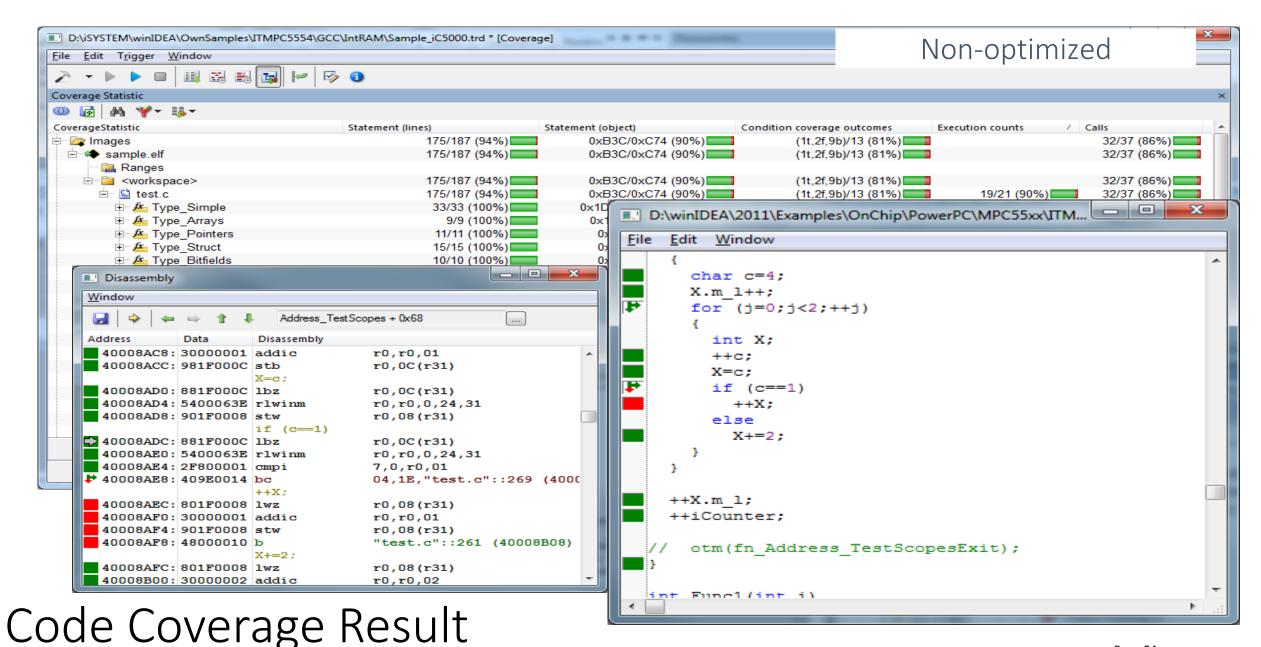
- The amount of time a coverage session can run depends on
  - The trace buffer size
  - Trace port or onchip trace buffer
  - The upload speed to the PC
  - Upload while sampling possibility
  - CPU speed / Trace Port Speed
- Object code level results are mostly conclusive, except
  - Arithmetic op-codes are used instead of logical ones
    - -> the conditional outcomes are undetectable (at least in real-time trace)
- Possible Limitations of Source Code Coverage

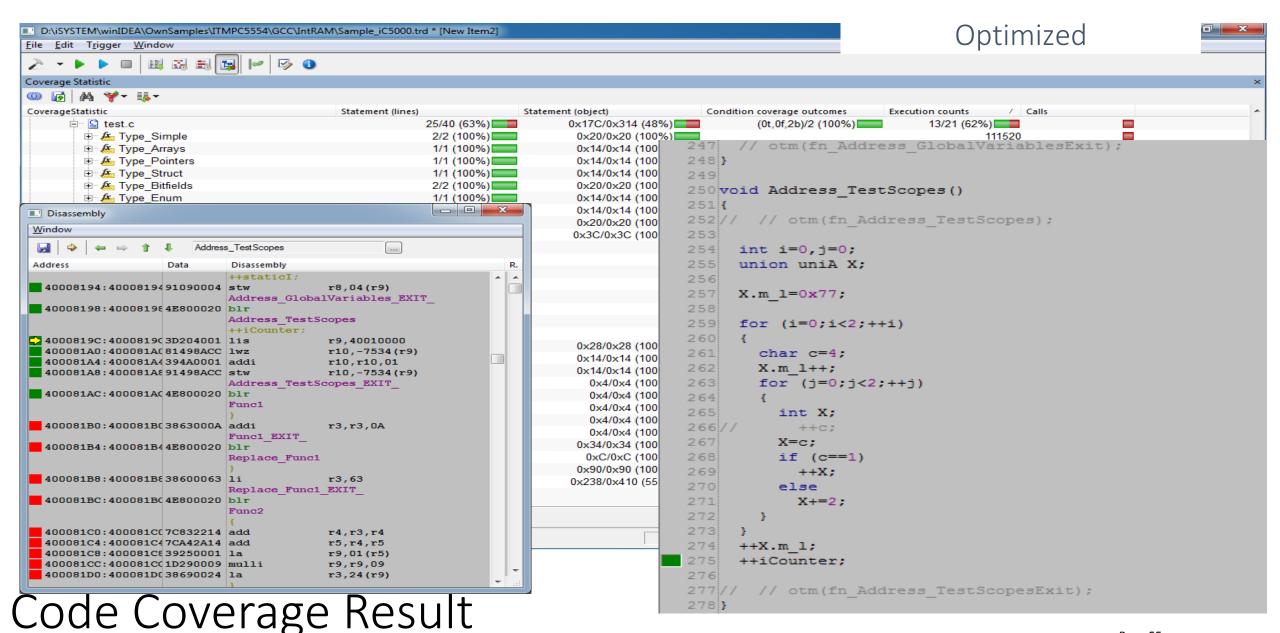
Object code does not correspond to the source code because of

- Compiler optimization
- Complex conditions
- Libraries
- Conversion





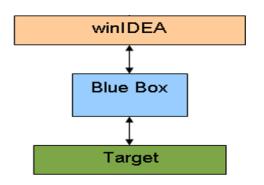


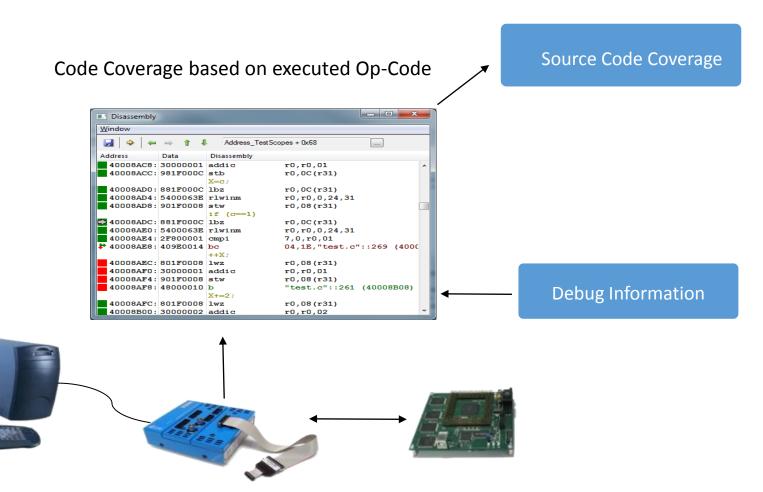




## Code Coverage Execution

- Setup is a typical debug scenario
  - winIDEA (debug IDE)
  - Blue Box for debuging
  - Target
- Trace is mandatory
  - Needed for coverage





#### Summary

#### Code Coverage



#### Features

- Analysis of the trace buffer and comparison to the source code, specifically for all addresses executed while application is running (execution coverage)
- Creates reports to be used for certification documents

#### Usage

- Statement coverage (executed / not executed)
- Condition coverage (analysis of conditional branch instructions and statements)
- Call Coverage (analysis of call instructions)
- Off-line operation mode (analysis after recording)

#### Benefits

- Coverage of NON-INSTRUMENTED and optimized code over a long period of time
- Identify "dead" code
- Save, and RESTART or CONTINUE coverage sessions
- Report/Export format: HTML, XML, text
- Remote control and automate coverage sessions with iSYSTEM's API



#### Test Report Generation



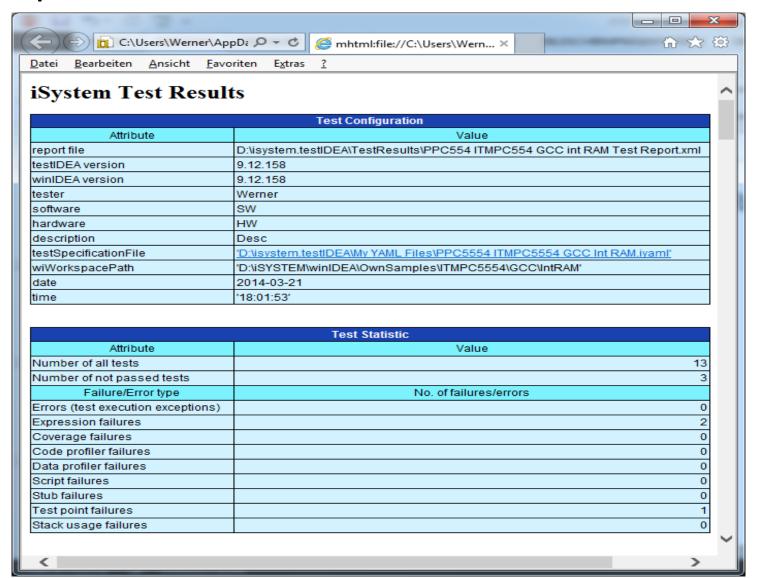


## Test Report Generation

✓ Save Test Report	x -					
Report contents:	Full report     Errors only					
Output format:						
Output format co	Output format configuration					
XSLT: < built-in:	> itestResult.blue.xslt ▼ Browse					
Output File:	D:\isystem.testIDEA\TestResults\PPC554 ITMPC554 GCC int RAM Test Report.xml					
Include test spe	ecifications					
Open default br	rowser after save					
Tester:	Werner					
Use custom dat	te and time					
Date: 21.03.2014 Time: 17:57:24						
Test Environmen						
Software: SW						
Hardware: HW						
Description: Desc						
	OK Cont					
	OK Cancel					

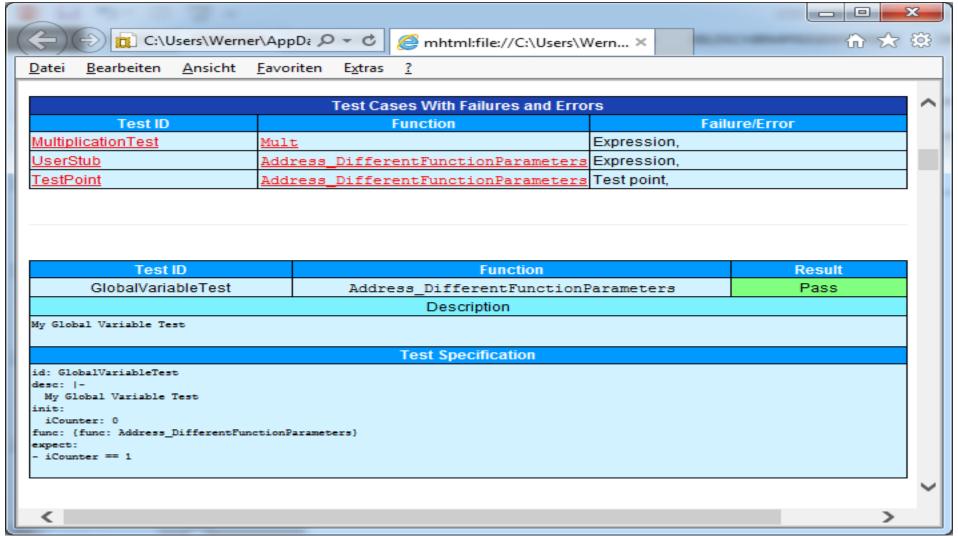


#### Test Report - Overview





## Test Report – Individual Results



Page 61



#### **EMBEDDED TOOLS FOR SINGLE AND MULTI-CORE**

Software Development, Analysis, Test Automation and Certification

## Do not hestitate to contact us for more information. Unit Test with Code Coverage



Tel: +31 – 345-545.535 / gerard@indes.com / www.indes.com